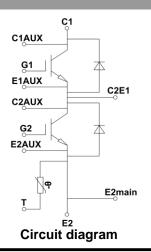
Silicon N-channel IGBT 3300V F version

FEATURES

- * High current density package
- * Low stray inductance & low Rth(j-c)
- * Half-bridge (2in1)
- * Built in temperature sensor
- * Scalable large current easily handled by paralleling
- * Equipped with current sensing terminals

ABSOLUTE MAXIMUM RATINGS (Tc=25°C)



Item		Symbol	Unit	MBM450FS33F		
Collector Emitter Voltage		VCES	V	3,300		
Gate Emitter Voltage		V _{GES}	V	±20		
Collector Current	DC	lc	Δ	450		
Collector Current	1ms	Ісм	A	900		
Forward Current	DC	IF	А	450		
Forward Current	1ms	IFM	A	900		
Junction Temperature		T _{vj op}	°C	-50 ~ +150		
Storage Temperature		T _{stg}	°C	-55 ~ +150		
Isolation Voltage		Viso	V _{RMS}	6,000(AC 1 minute)		
Screw Torque	Terminals (M3/M8)	М	N∙m	0.8/15		
	Mounting (M6)	М		6.0 (1)		

Notes: (1) Recommended Value 5.5±0.5N·m

ELECTRICAL CHARACTERISTICS

ltem		Symbol	Unit	Min.	Тур.	Max.	Test Conditions
			•	-	-	0.30	V _{CE} =3,300V, V _{GE} =0V, T _{vi} =25°C
Collector Emitter Cut-Off Current		ICES	mA	-	15	50	Vce=3,300V, Vge=0V, Tvj=150°C
Gate Emitter Leakage Current		I _{GES}	nA	-500	-	+500	V _{GE} =±20V, V _{CE} =0V, T _{vi} =25°C
Collector Emitter Saturation Voltage		V _{CEsat}	V	-	2.25	-	Ic=450A, V _{GE} =15V, T _{vj} =25°C
				2.50	3.05	3.50	I _C =450A, V _{GE} =15V, T _{vj} =150°C
Gate Emitter Threshold Voltage		V _{GE(th)}	V	5.5	6.5	7.5	Vc∈=10V, Ic=450mA, T _{vj} =25°C
Input Capacitance		Cies	nF	-	24	-	V _{CE} =10V, V _{GE} =0V, f=100kHz, T _{vj} =25°C
Internal Gate Resistance		R _G (int)	Ω	-	6.2	-	V _{CE} =10V, V _{GE} =0V, f=100kHz, T _{vj} =25°C
Turn On Delay Time		t _{d(on)}		-	0.48	-	Vcc=1800V, Ic=450A
Rise Time		tr	μs	-	0.12	-	Ls=40nH
Turn Off Delay Time		t _{d(off)}		-	1.10	-	$R_{G}(\text{on/off})=6.8\Omega/12\Omega \qquad (2)$
Fall Time		t _f		-	1.30	-	V _{GE} =±15V, T _{vj} =150°C
Forward Voltage Drop		VF	V	-	2.25	-	IF=450A, VGE=0V, Tvj=25°C
				2.10	2.45	2.80	I _F =450A, V _{GE} =0V, T _{vj} =150°C
Reverse Recovery Time		trr	μs	-	1.10	-	V _{CC} =1800V, I _F =450A, Ls =40nH T _{vi} =150°C
Turn-on Loss per Pulse		Eon	J/P	-	0.73	-	V _{cc} =1800V, Ic=450A, Ls =40nH
Turn-off Loss per Pulse		Eoff	J/P	-	0.63	-	$R_{G}(\text{on/off})=6.8\Omega/12\Omega$ (2)
Reverse Recovery Loss per Pulse		Err	J/P	-	0.68	-	V _{GE} =±15V, T _{vj} =150°C
Short Circuit Pulse Width		t _{sc}	μS	10	-	-	Vcc=2200V,Ls=40nH
							$R_G(on/off)=6.8/68 \Omega$, $V_{GE}=\pm 15V$, $T_{V}=150^{\circ}C$
Stray Inductance Module		LSCE	nH	-	9	-	Between C1(main) and E2(main)
NTC-Thermistor	Resistance	R ₂₅	kΩ	-	5	-	Tc=25 °C
	Deviation	∆R/R	%	-5		5	Tc=25 °C
	B-constant	B(25/50)	K	-	3375	-	Between 25°C and 50°C
Thormal Impadance	IGBT	Rth(j-c)	K/W	-	-	0.035	Junction to case
Thermal Impedance	FWD	Rth(j-c)		-	-	0.055	
Contact Thermal Impedance		Rth(c-f)	K/W	-	0.02	-	Case to fin (per 1 arm)

Notes: (2) R_{G} value is a test condition value for evaluation, not recommended value.

Please determine the suitable R_{g} value by measuring switching behavior and checking results with the respective SOA.

* Please contact our representatives at order. * For improvement, specifications are subject to change without notice.

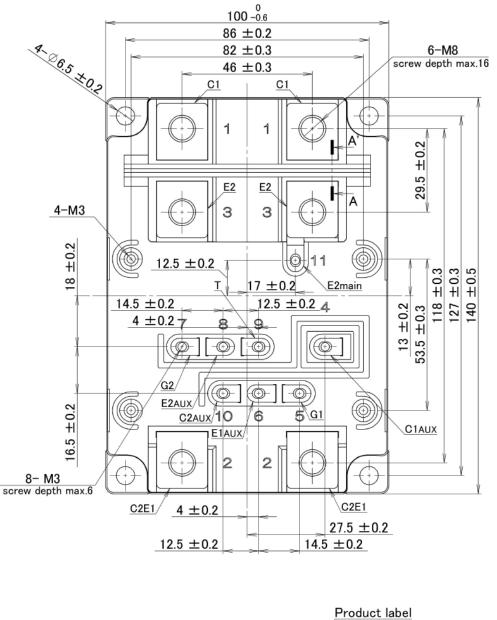
* For actual application, please confirm this spec sheet is the newest revision.

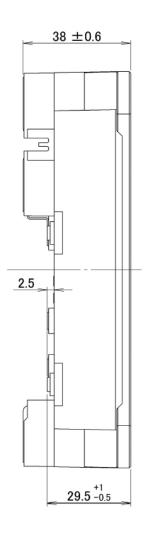
* ELECTRICAL CHARACTERISTIC items shown in above table are according to IEC 60747-2 and IEC 60747-9.

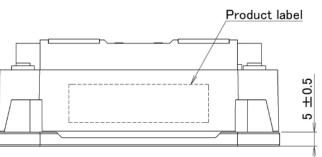


OUTLINE DRAWING

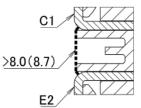
Unit in mm



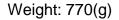




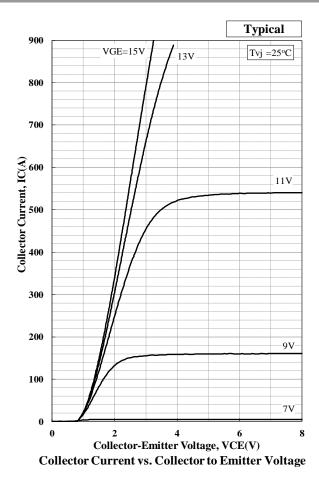
Clearance between C1 and E2 terminal

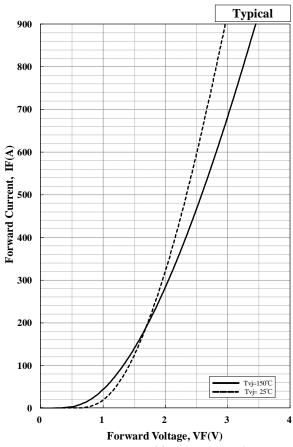


<A-A' cross section>

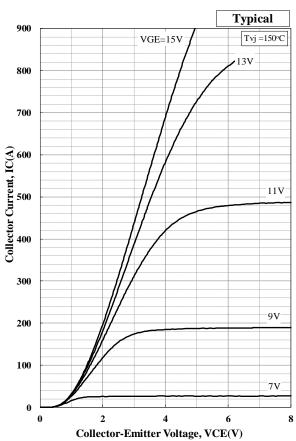




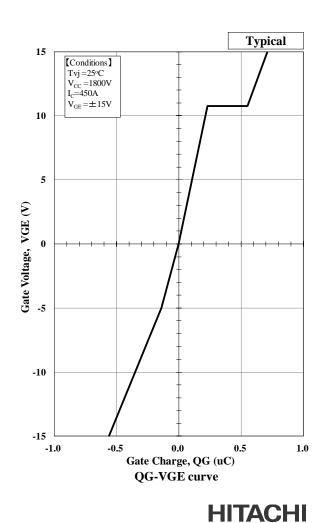




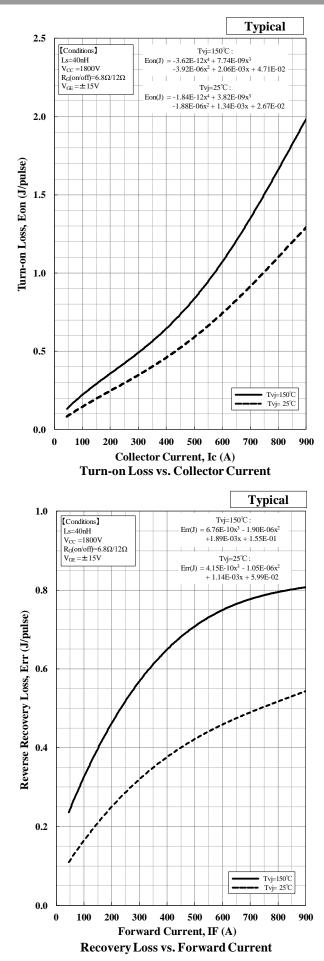
Forward Voltage of free-wheeling diode

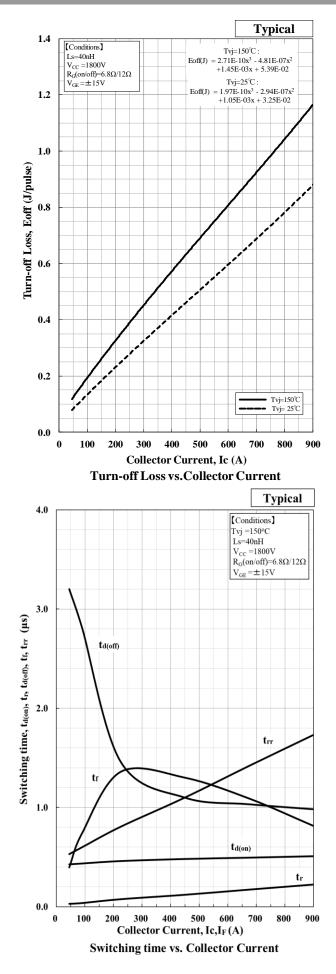


Collector Current vs. Collector to Emitter Voltage

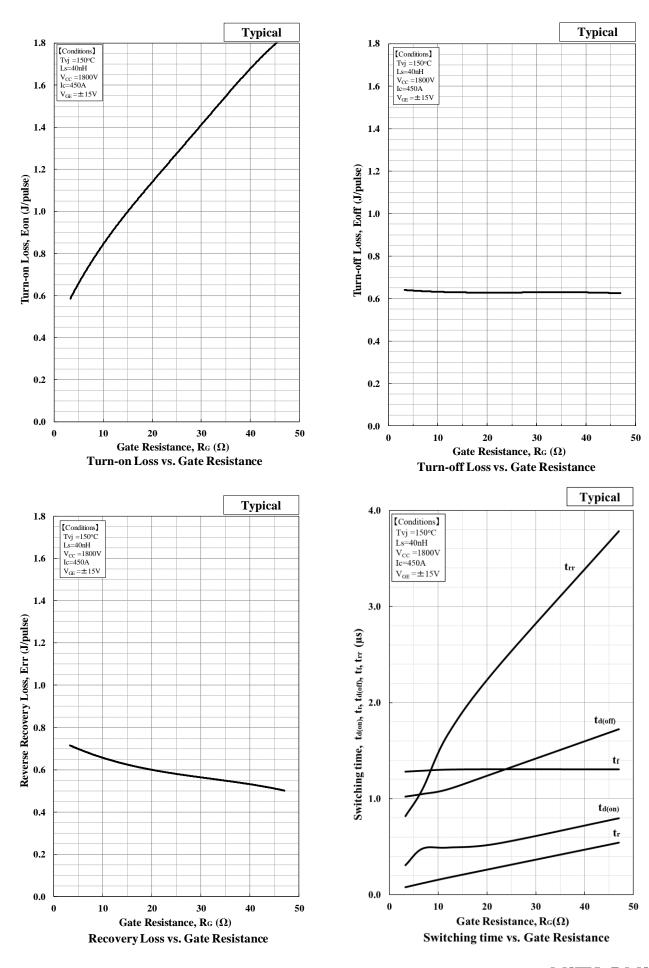


Inspire the Next

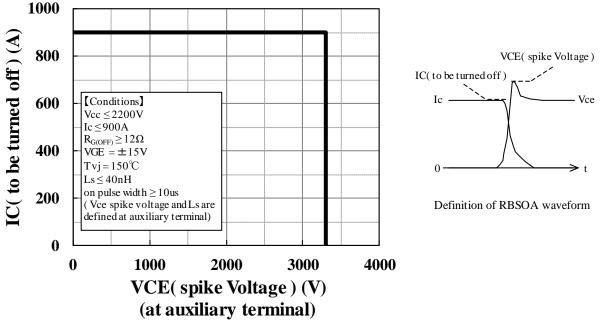




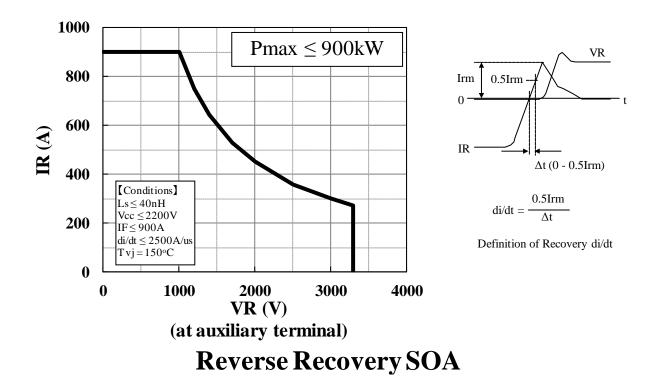
HITACHI Inspire the Next



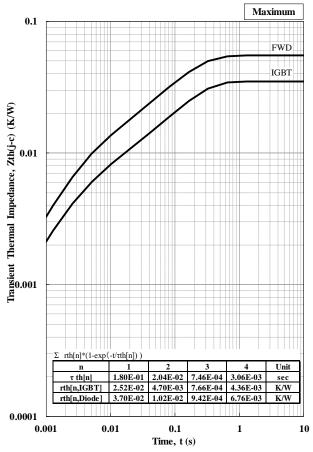




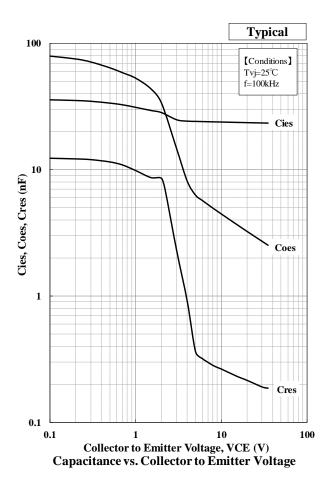
Reverse bias safe operation area (RBSOA)

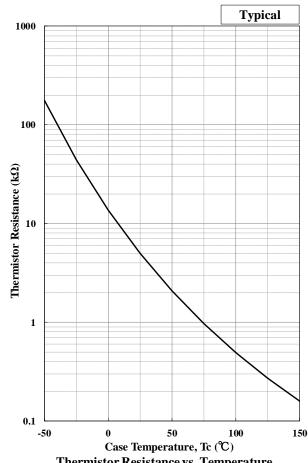






Transient Thermal Impedance Curve





Thermistor Resistance vs. Temperature



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